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U.S. Department of Commerce, Patent and Trademark		Atty. Docket No.	Application No.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		TNCR.169US2	10/729,609
(Use several sheets if necessary)		Applicant(s)	Conf. No.
		Thomas McWaid	2888
		Filing Date	Group
		December 5, 2003	2856

U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>[Signature]</i>	1	2,691,887	Oct., 1954	Rinker..	—	—	
	2	2,728,222	Dec., 1955	Becker et al.	—	—	
	3	3,283,568	Nov., 1966	Reason..	—	—	
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	6	4,441,177	Apr., 1984	Groh et al.	—	—	
	7	4,574,625	Mar., 1986	Olasz et al.	—	—	
	8	4,641,773	Feb., 1987	Morino et al.	—	—	
	9	4,669,300	Jun., 1987	Hall et al.	—	—	
	10	4,724,318	Feb., 1988	Binnig.	—	—	
	11	4,883,959	Nov., 1989	Hosoki et al.	—	—	
	12	4,902,892	Feb. 1990	Okayama et al.	250	307	
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	24	5,412,980	May., 1995	Elings et al.	—	—	
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Examiner

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01 April 2005

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<i>Dr</i>	27	5,426,302	Jun., 1995	Marchman et al.	—	—	
<i>Dr</i>	28	5,481,521	Jan., 1996	Washizawa et al.	—	—	
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<i>Dr</i>	37	5,866,806	Feb. 1999	Samsavar et al.	73	105	
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Foreign Patent Documents

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
<i>Dr</i>	39	0361932	Sep., 1989	EP.	—	—		
<i>Dr</i>	40	0536827	Sep., 1992	EP.	—	—		
<i>Dr</i>	41	0594362	Oct., 1993	EP.	—	—		
<i>Dr</i>	42	0633450	Jun., 1994	EP.	—	—		
<i>Dr</i>	43	2249910	Oct., 1990	JP	—	—		
<i>Dr</i>	44	2009409	Jun., 1979	GB	73	105		
<i>Dr</i>	45	WO 88/04047	Jun., 1988	WO.	—	—		
<i>Dr</i>	46	WO 94/08204	Apr., 1994	WO	—	—		
<i>Dr</i>	47	WO 94/25888	Nov., 1994	WO.	—	—		
<i>Dr</i>	48	85920	Feb. 1998	WO.	73	105		

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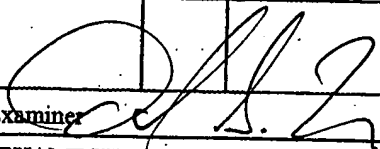
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
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<i>Dr</i>	50.	"From Molecules to Cells: Imaging Soft Samples with the Atomic Force Microscope", M. Radmacher et al., Science, vol. 257, Sep. 25, 1992, pp. 1900-1905.	
<i>Dr</i>	51.	"Dimensional Metrology of Phase-Shifting Masks with Scanning Probe Microscopes," J.E. Griffith et al., SPIE, vol. 2087, Photomask Technology and Management, 1993, pp. 107-118.	
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<i>Dr</i>	58.	"Scanning Tunneling Microscopy," G. Binnig et al., Helvetica Physica Acts, vol. 55, 1982, pp. 726-735.	
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<i>Dr</i>	61.	"Design and Assessment of Monolithic High Precision Translation Mechanisms," S.T. Smith et al., Journal of Physics E: Scientific Instruments, vol. 20, Aug. 1987, pp. 977-983.	
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<i>Jr</i>	62	"Novel Optical Approach to Atomic Force Microscopy," G. Meyer et al., Applied Physics Letters, vol. 53, No. 12, Sep. 1988, pp. 1045-1047.	
<i>Jr</i>	63	"Long Range Constant Force Profiling for Measurement of Engineering Surfaces," L.P. Howard, Review of Scientific Instruments, vol. 63, No. 10, Oct. 1992, pp. 4289-4295.	
<i>Jr</i>	64	"The National Institute of Standards and Technology Molecular Measuring Machine Project: Metrology and Precision Engineering Design," E.C. Teague, J. Vac. Sci. Technol. B, vol. 7, No. 6, Nov/Dec. 1989, pp. 1898-1902.	
<i>Jr</i>	65	"Evaluating the Sensitivity of a Fiber-Optic Displacement Sensor," W.C. Oliver, Nano Instruments, Inc., Technotes, no date available.	
<i>Jr</i>	66	"To Measure a Molecule," F. Flam, pp. 21-24, no date available.	
<i>Jr</i>	67	"The National Institute of Standards and Technology Molecular Measuring Machine: A Long-Range Scanning Tunneling Microscope for Dimensional Metrology," E.C. Teague, Microbeam Analysis, 1989, pp. 545-547.	
<i>Jr</i>	68	"Products for Micropositioning," Product Information Brochure published by Physik Instrumente (PI) GmbH & Co., no date available.	
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<i>Jr</i>	71	"Nanometrology," E.C. Teague; Proceedings of Scanned Probe Microscopy; STM and Beyond, an Engineering Foundation Conference, Santa Barbara, CA Jan. 1991.	
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